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Engineering complex oxide interfaces for oxide electronics

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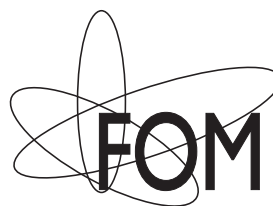
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Engineering complex oxide interfaces for
oxide electronics

Saurabh Roy



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dedicated to my loved ones..

Contents

1	Introduction and Outline	1
1.1	Introduction	1
1.2	Scope of this thesis	4
	Bibliography	6
2	Experimental Techniques	7
2.1	Introduction	7
2.2	Chemical treatment and substrate termination of SrTiO ₃	8
2.3	Deposition of thin films	9
2.3.1	Pulsed laser deposition (PLD) and reflection high energy elec- tron diffraction (RHEED)	9
2.3.2	Electron beam evaporation	15
2.4	Scanning Probe Microscopy	15
2.4.1	Atomic force microscopy	16
2.4.2	Conducting atomic force microscopy	18
2.4.3	Piezoresponse force microscopy	18
2.5	X-ray diffraction	22
2.6	Physical and magnetic property measurement of thin films	23
2.6.1	Physical property measurement system (PPMS)	23
2.6.2	Magnetic property measurement system (MPMS)	23
2.7	Device fabrication	24
2.8	Ballistic electron emission microscopy (BEEM)	25
2.9	Conclusions	28
	Bibliography	29

3	Physics of Schottky barrier and Ballistic Electron Emission Microscopy	31
3.1	Introduction	31
3.2	Formation of a Schottky barrier	32
3.2.1	The Schottky-Mott relationship	34
3.2.2	Fermi-level pinning at semiconductor surface	35
3.2.3	Metal induced gap states model	36
3.2.4	Bond-polarization theory	37
3.3	Ballistic electron emission microscopy	39
3.3.1	Theory	40
3.3.2	BEEM transport models	44
3.4	Summary	45
	Bibliography	47
4	Growth, characterization and hot electron transport through SrRuO₃ thin films	49
4.1	Introduction and Motivation	49
4.2	Growth of SrRuO ₃ thin films	52
4.3	Structural characterization of SrRuO ₃ thin films	53
4.4	Magnetic properties of SrRuO ₃ thin films	55
4.5	Electrical transport properties of SrRuO ₃ thin films	58
4.6	Nanoscale electronic transport across SrRuO ₃ / Nb:SrTiO ₃	59
4.6.1	Thickness and temperature dependent BEEM transmission	60
4.6.2	Influence of interface and film thickness on electronic transport	63
4.6.3	Results of <i>Ab initio</i> study of SrRuO ₃ /SrTiO ₃ (001) interfaces	65
4.6.4	Variation of the electronic and structural properties of the interface at LT and RT	66
4.7	Conclusions	69
	Bibliography	71
5	Engineering interfacial energy profile across non-polar heterointerfaces	73
5.1	Introduction and Motivation	73
5.2	Growth and fabrication of SrRuO ₃ devices	75
5.3	Results and discussions	79
5.4	Conclusion	92
	Bibliography	94

6 Influence of ferroelectric polarization on hot electron transport through BiFeO₃	97
6.1 Introduction and Motivation	97
6.2 Interface control of polarization state	102
6.3 Sample growth, fabrication and measurement technique	103
6.4 Polarization control of energy band alignments	105
6.5 Results and discussions	109
6.6 Conclusion	114
Bibliography	115
7 Towards probing ferroelectric domain walls by BEEM	117
7.1 Introduction and Motivation	117
7.2 Growth and fabrication	120
7.3 Results and discussions	123
7.4 Conclusions and outlook	127
Bibliography	128
Summary	129
Samenvatting	133
Acknowledgements	137
Publications	141
Curriculum Vitae	142

